ELSEVIER

Ultramicroscopy 57 (1995) 423–426

ultramicroscopy

Author index to volume 57

Abstreiter, G., see Kolb 57 (1995) 208
Allen, E.V., see Dunn 57 (1995) 113
Anderson, G.A., see Dunn 57 (1995) 113
Aoyama, K., K. Ogawa, Y. Kimura and Y. Fujiyoshi, A method for 2D crystallization of soluble proteins at liquid–liquid interface 57 (1995) 345
Ataka, T., see Fujihira 57 (1995) 118
Ataka, T., see Muramatsu 57 (1995) 141
Ataka, T., see Fujihira 57 (1995) 176

Bachelot, R., see Gleyzes 57 (1995) 318
Balasubramaniam, S., see Cloninger 57 (1995) 223
Barchiesi, D. and D. Van Labeke, A perturbative diffraction theory of a multilayer system: applications to near-field optical microscopy SNOM and STOM 57 (1995) 196
Barreteau, C. and F. Ducastelle, The orthogonalized plane-wave method applied to the calculation of dynamical effects in electron diffraction 57 (1995) 11
Binks, C.J., see Williamson 57 (1995) 235
Boccara, A.C., see Gleyzes 57 (1995) 318
Böhm, G., see Kolb 57 (1995) 208
Bölger, B., see Moers 57 (1995) 298
Bonnet, N., Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis 57 (1995) 17
Boudreau, B.D., see Cloninger 57 (1995) 223
Boyd, J.T., see Choo 57 (1995) 124

Cates, C., see Ghaemi 57 (1995) 165
Cavalcoli, D., G. Matteucci and M. Muccini, Simulation of electron holographic contour maps of linear charged dislocations 57 (1995) 385
Chau, K.-L., see Kirkland 57 (1995) 355
Chen, Y. and R.K. Kupka, Analysis of the near field image formation of dielectric gratings 57 (1995) 153
Chiba, N., see Muramatsu 57 (1995) 141
Choo, A.G., M.H. Chudgar, H.E. Jackson, G.N. De Brabander, M. Kumar and J.T. Boyd, Photon scanning tunneling microscopy of optical channel waveguides 57 (1995) 124
Christensen, D.A., Analysis of near field tip patterns including object interaction using finite-difference time-domain calculations 57 (1995) 189
Chudgar, M.H., see Choo 57 (1995) 124
Cline, J.A. and M. Isaacson, Comparison of different modes of reflection in near-field optical imaging 57 (1995) 147
Cloninger, T.L., S. Balasubramaniam, B.D. Boudreau, J. Raja and R.J. Hocken, A simple technique for screening near-field probes 57 (1995) 223
Cowley, J.M., Chromatic coherence and inelastic scattering in electron holography 57 (1995) 327
Cowley, J.M., see Huang 57 (1995) 391
Creuzet, F., see Piednoir 57 (1995) 282

Dawson, P., K.W. Smith, F. de Fornel and J.-P. Goudonnet, Imaging of surface plasmon launch and propagation using a photon scanning tunneling microscope 57 (1995) 287
De Brabander, G.N., see Choo 57 (1995) 124
De Fornel, F., see Dawson 57 (1995) 287
De Hollander, R.B.G., N.F. van Hulst and R.P.H. Kooyman, Near field plasmon and force microscopy 57 (1995) 263
De Ruijter, W.J., R. Sharma, M.R. McCartney and D.J. Smith, Measurement of lattice-fringe vectors from digital HREM images: experimental precision 57 (1995) 409
D'Hoore, A., see Vinckier 57 (1995) 337
Dietzsch, Ch., see Driesel 57 (1995) 45
Dorset, D.L., S. Kopp, J.R. Fryer and W.F. Tivol, The Sayre equation in electron crystallography 57 (1995) 59
Dravid, V.P., see Zhang 57 (1995) 103
Driesel, W., Ch. Dietzsch, H. Niedrig and B. Praprotnik, HV TEM in situ investigations of the tip shape of a gallium liquid-metal ion/electron emitter 57 (1995) 45
Ducastelle, F., see Barreteau 57 (1995) 11
Duncan, M.D., see Seaver 57 (1995) 219
Dunn, R.C., E.V. Allen, S.A. Joyce, G.A. Anderson and X.S. Xie, Near-field fluorescent imaging of single proteins 57 (1995) 113

Elsevier Science B.V.

Dunn, R.C. and X.S. Xie, Characterization of the temporal behavior of ultrashort pulses emerging from a near-field fiber probe 57 (1995) 169

Elich, K., see Voigt-Martin 57 (1995) 29
Engelborghs, Y., see Vinckier 57 (1995) 337

Froehlich, F., see Kann 57 (1995) 251
Frost, A.E., see Seaver 57 (1995) 219
Fryer, J.R., see Dorset 57 (1995) 59
Fujihira, M., H. Monobe, H. Muramatsu and T. Ataka, Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM 57 (1995) 118
Fujihira, M., see Muramatsu 57 (1995) 141
Fujihira, M., H. Monobe, H. Muramatsu and T. Ataka, Near-field optical microscopic recording on Langmuir–Blodgett (LB) films and chemically modified surfaces 57 (1995) 176
Fujiyoshi, Y., see Aoyama 57 (1995) 345

Gajdardziska-Josifovska, M., see Huang 57 (1995) 391
Ghaemi, H., C. Cates and B.B. Goldberg, Low temperature near field spectroscopy and microscopy 57 (1995) 165
Gleyzes, P., A.C. Boccara and R. Bachelot, Near field optical microscopy using a metallic vibrating tip 57 (1995) 318
Goldberg, B.B., see Ghaemi 57 (1995) 165
Goudonnet, J.-P., see Dawson 57 (1995) 287
Greffet, J.-J., see Sentenac 57 (1995) 246
Gurevich, V.S. and M.N. Libenson, Surface polaritons propagation along micropipettes 57 (1995) 277

Hallen, H.D., see LaRosa 57 (1995) 303
Han, P., see Zhang 57 (1995) 103
Hecht, B., H. Heinzelmann and D.W. Pohl, Combined aperture SNOM/PSTM: best of both worlds? 57 (1995) 228
Heinzelmann, H., see Hecht 57 (1995) 228
Hellemans, L., see Vinckier 57 (1995) 337
Hermann, C., see Safarov 57 (1995) 270
Hertz, H.M., L. Malmqvist, L. Rosengren and K. Ljungberg, Optically trapped non-linear particles as probes for scanning near-field optical microscopy 57 (1995) 309
Heyvaert, I., see Vinckier 57 (1995) 337
Hocken, R.J., see Cloninger 57 (1995) 223
Holton, M., see Valaskovic 57 (1995) 212
Huang, Y., M. Gajdardziska-Josifovska and J.M. Cowley, REM in a UHV TEM for the observation of dynamic phase transformation processes on the $Cu_3Au(111)$ surface 57 (1995) 391

Inouye, Y., see Kawata 57 (1995) 313
Isaacson, M., Foreword to Near Field Optics 57 (1995) vii
Isaacson, M., see Cline 57 (1995) 147
Ishikawa, T. and T. Wakabayashi, Proposal of alignment-independent classification of electron microscopic images with helical symmetry and its application to reconstituted thin filaments of skeletal muscle 57 (1995) 91

Jackson, H.E., see Choo 57 (1995) 124
Jahncke, C.L., see LaRosa 57 (1995) 303
Joyce, S.A., see Dunn 57 (1995) 113
Judkins, J., see Kann 57 (1995) 251

Kann, J.L., T.D. Milster, F. Froehlich, R.W. Ziolkowski and J. Judkins, Numerical analysis of a two-dimensional near-field probe 57 (1995) 251
Karraï, K., see Kolb 57 (1995) 208
Kawasaki, M., see Kirkland 57 (1995) 355
Kawata, S. and Y. Inouye, Scanning probe optical microscopy using a metallic probe tip 57 (1995) 313
Kimura, Y., see Aoyama 57 (1995) 345
Kipp, S., R. Lacmann and M.A. Schneeweiss, Problems in temperature control performing in situ investigations with the scanning force microscope 57 (1995) 333
Kirkland, A.I., W.O. Saxton, K.-L. Chau, K. Tsuno and M. Kawasaki, Super-resolution by aperture synthesis: tilt series reconstruction in CTEM 57 (1995) 355
Kolb, G., C. Obermüller, K. Karraï, G. Abstreiter, G. Böhm, G. Tränkle and G. Weimann, Photodetector with subwavelength spatial resolution 57 (1995) 208
Kooyman, R.P.H., see De Hollander 57 (1995) 263
Kopelman, R., see Smith 57 (1995) 173
Kopelman, R., see Monson 57 (1995) 257
Kopp, S., see Dorset 57 (1995) 59
Kosobukin, V.A., see Safarov 57 (1995) 270
Kovacs, J., see Tsai 57 (1995) 130
Krumbügel, M.A., see Totzeck 57 (1995) 160
Kumar, M., see Choo 57 (1995) 124
Kupka, R.K., see Chen 57 (1995) 153

Lacmann, R., see Kipp 57 (1995) 333
Lampel, G., see Safarov 57 (1995) 270
Langmore, J.P., see Monson 57 (1995) 257
LaRosa, A., C.L. Jahncke and H.D. Hallen, Time as a contrast mechanism in near-field imaging 57 (1995) 303
Libenson, M.N., see Gurevich 57 (1995) 277
Licoppe, C., see Piednoir 57 (1995) 282
Ljungberg, K., see Hertz 57 (1995) 309

Malmqvist, L., see Hertz 57 (1995) 309
Marks, L.D., see Zhang 57 (1995) 103
Marlière, C., see Safarov 57 (1995) 270
Matteucci, G., see Cavalcoli 57 (1995) 385
McCartney, M.R., see De Ruijter 57 (1995) 409
McKittrick, T., see Vinckier 57 (1995) 337
Merritt, G., see Monson 57 (1995) 257
Miles, M.J., see Williamson 57 (1995) 235
Milster, T.D., see Kann 57 (1995) 251
Moers, M.H.P., N.F. van Hulst, A.G.T. Ruiter and B. Bölger, Optical contrast in near-field techniques 57 (1995) 298
Monobe, H., see Fujihira 57 (1995) 118
Monobe, H., see Muramatsu 57 (1995) 141
Monobe, H., see Fujihira 57 (1995) 176
Monson, E., G. Merritt, S. Smith, J.P. Langmore and R. Kopelman, Implementation of an NSOM system for fluorescence microscopy 57 (1995) 257
Morrison, G.H., see Valaskovic 57 (1995) 212
Moskovits, M., see Tsai 57 (1995) 130
Muccini, M., see Cavalcoli 57 (1995) 385
Muramatsu, H., see Fujihira 57 (1995) 118
Muramatsu, H., N. Chiba, T. Ataka, H. Monobe and M. Fujihira, Scanning near-field optic/atomic-force microscopy 57 (1995) 141
Muramatsu, H., see Fujihira 57 (1995) 176

Niedrig, H., see Driesel 57 (1995) 45
Norris, T., see Smith 57 (1995) 173
Novotny, L., D.W. Pohl and P. Regli, Near-field, far-field and imaging properties of the 2D aperture SNOM 57 (1995) 180

Obermüller, C., see Kolb 57 (1995) 208
Ogawa, K., see Aoyama 57 (1995) 345
Orr, B.G., see Smith 57 (1995) 173
Ortéga, J.M., see Piednoir 57 (1995) 282

Paesler, M.A., see Yakobson 57 (1995) 204
Paesler, M.A., see Yakobson 57 (1995) 241
Payne, D.A., see Zhang 57 (1995) 103
Peng, L.-M. and J.M. Zuo, Direct retrieval of crystal structure factors in THEED 57 (1995) 1
Peretti, J., see Safarov 57 (1995) 270
Piednoir, A., F. Creuzet, C. Licoppe and J.M. Ortéga, Locally resolved infrared spectroscopy 57 (1995) 282
Pohl, D.W., see Novotny 57 (1995) 180
Pohl, D.W., see Hecht 57 (1995) 228
Praprotnik, B., see Driesel 57 (1995) 45

Raja, J., see Cloninger 57 (1995) 223
Regli, P., see Novotny 57 (1995) 180
Rogers, J.K., see Toledo-Crow 57 (1995) 293
Rosengren, L., see Hertz 57 (1995) 309
Ruiter, A.G.T., see Moers 57 (1995) 298

Safarov, V.I., V.A. Kosobukin, C. Hermann, G. Lampel, C. Marlière and J. Peretti, Near-field magneto-optics with polarization sensitive STOM 57 (1995) 270
Saxton, W.O., see Kirkland 57 (1995) 355
Schneeweiss, M.A., see Kipp 57 (1995) 333
Seaver, M., M.D. Duncan and A.E. Frost, Near-field optical microscopy at the liquid/air interface 57 (1995) 219
Seiferth, F., see Toledo-Crow 57 (1995) 293
Sentenac, A. and J.-J. Greffet, Study of the features of PSTM images by means of a perturbative approach 57 (1995) 246
Sharma, R., see De Ruijter 57 (1995) 409
Smith, D.J., see De Ruijter 57 (1995) 409
Smith, K.W., see Dawson 57 (1995) 287
Smith, S., B.G. Orr, R. Kopelman and T. Norris, 100 femtosecond/100 nanometer near-field probe 57 (1995) 173
Smith, S., see Monson 57 (1995) 257
Su, D.S. and H.F. Wang, Atomic ratios determined by EELS under parallel and convergent illumination conditions 57 (1995) 323

Tivol, W.F., see Dorset 57 (1995) 59
Toledo-Crow, R., J.K. Rogers, F. Seiferth and M. Vaez-Iravani, Contrast mechanisms and imaging modes in near field optical microscopy 57 (1995) 293
Totzeck, M. and M.A. Krumbügel, Test of various diffraction theories in the near field of phase objects 57 (1995) 160
Tränkle, G., see Kolb 57 (1995) 208
Tsai, D.P., J. Kovacs and M. Moskovits, Applications of apertured photon scanning tunnelling microscopy (APSTM) 57 (1995) 130
Tsuno, K., see Kirkland 57 (1995) 355

Vaez-Iravani, M., see Toledo-Crow 57 (1995) 293
Valaskovic, G.A., M. Holton and G.H. Morrison, Biological near-field scanning optical microscopy: instrumentation and sample issues for shear-force feedback 57 (1995) 212
Van Haesendonck, C., see Vinckier 57 (1995) 337
Van Hulst, N.F., see De Hollander 57 (1995) 263
Van Hulst, N.F., see Moers 57 (1995) 298
Van Labeke, D., see Barchiesi 57 (1995) 196
Vinckier, A., I. Heyvaert, A. D'Hoore, T. McKittrick, C. Van Haesendonck, Y. Engelborghs and L. Hellemans, Immobilizing and imaging microtubules by atomic force microscopy 57 (1995) 337
Voigt-Martin, I.G., D.H. Yan, R. Wortmann and K. Elich, The use of simulation methods to obtain the structure and conformation of 10-cyano-9,9′-bianthryl by electron diffraction and high-resolution imaging 57 (1995) 29

Wakabayashi, T., see Ishikawa 57 (1995) 91
Wang, H.F., see Su 57 (1995) 323
Wang, Y.Y., see Zhang 57 (1995) 103
Weickenmeier, A.L., see Zuo 57 (1995) 375
Weimann, G., see Kolb 57 (1995) 208
Williamson, R.L., C.J. Binks and M.J. Miles, Scanning tunnelling optical microscopy – breaking a resolution barrier? 57 (1995) 235
Wortmann, R., see Voigt-Martin 57 (1995) 29

Xie, X.S., see Dunn 57 (1995) 113
Xie, X.S., see Dunn 57 (1995) 169

Yakobson, B.I. and M.A. Paesler, Tip optics for illumination NSOM: extended-zone approach 57 (1995) 204
Yakobson, B.I. and M.A. Paesler, Kinetics, morphology and pulling regimes for sensing tips in near-field microscopy 57 (1995) 241
Yan, D.H., see Voigt-Martin 57 (1995) 29

Zhang, H., see Zhang 57 (1995) 103
Zhang, H., L.D. Marks, Y.Y. Wang, H. Zhang, V.P. Dravid, P. Han and D.A. Payne, Structure of planar defects in $(Sr_{0.9}Ca_{0.3})_{1.1}CuO_2$ infinite-layer superconductors by quantitative high-resolution electron microscopy 57 (1995) 103
Ziolkowski, R.W., see Kann 57 (1995) 251
Zuo, J.M., see Peng 57 (1995) 1
Zuo, J.M. and A.L. Weickenmeier, On the beam selection and convergence in the Bloch-wave method 57 (1995) 375

ELSEVIER

Ultramicroscopy 57 (1995) 429–431

ultramicroscopy

Subject index to volume 57

Atomic force microscopy (AFM)
Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 118
Scanning near-field optic/atomic-force microscopy, *Muramatsu, Chiba, Ataka, Monobe and Fujihira* 57 (1995) 141
Near field plasmon and force microscopy, *De Hollander, Van Hulst and Kooyman* 57 (1995) 263
Problems in temperature control performing in situ investigations with the scanning force microscope, *Kipp, Lacmann and Schneeweiss* 57 (1995) 333
Immobilizing and imaging microtubules by atomic force microscopy, *Vinckier, Heyvaert, D'Hoore, McKittrick, Van Haesendonck, Engelborghs and Hellemans* 57 (1995) 337

Convergent beam electron diffraction (CBED)
On the beam selection and convergence in the Bloch-wave method, *Zuo and Weickenmeier* 57 (1995) 375

Data processing / image processing
Preliminary investigation of two methods for the automatic handling of multivariate maps in microanalysis, *Bonnet* 57 (1995) 17
Proposal of alignment-independent classification of electron microscopic images with helical symmetry and its application to reconstituted thin filaments of skeletal muscle, *Ishikawa and Wakabayashi* 57 (1995) 91
Measurement of lattice-fringe vectors from digital HREM images: experimental precision, *De Ruijter, Sharma, McCartney and Smith* 57 (1995) 409

Editorials, Announcements, Comments, Reports, Historical notes
Foreword to Near Field Optics, *Isaacson* 57 (1995) vii

Electron diffraction
Direct retrieval of crystal structure factors in THEED, *Peng and Zuo* 57 (1995) 1
The orthogonalized plane-wave method applied to the calculation of dynamical effects in electron diffraction, *Barreteau and Ducastelle* 57 (1995) 11
The use of simulation methods to obtain the structure and conformation of 10-cyano-9,9′-bianthryl by electron diffraction and high-resolution imaging, *Voigt-Martin, Yan, Wortmann and Elich* 57 (1995) 29
The Sayre equation in electron crystallography, *Dorset, Kopp, Fryer and Tivol* 57 (1995) 59

Electron energy loss spectroscopy (EELS)
Atomic ratios determined by EELS under parallel and convergent illumination conditions, *Su and Wang* 57 (1995) 323

Electron sources
HV TEM in situ investigations of the tip shape of a gallium liquid-metal ion/electron emitter, *Driesel, Dietzsch, Niedrig and Praprotnik* 57 (1995) 45

Exit wave reconstruction
Super-resolution by aperture synthesis: tilt series reconstruction in CTEM, *Kirkland, Saxton, Chau, Tsuno and Kawasaki* 57 (1995) 355

High resolution transmission electron microscopy (HRTEM)
The use of simulation methods to obtain the structure and conformation of 10-cyano-9,9′-bianthryl by electron diffraction and high-resolution imaging, *Voigt-Martin, Yan, Wortmann and Elich* 57 (1995) 29
Structure of planar defects in $(Sr_{0.9}Ca_{0.3})_{1.1}CuO_2$ infinite-layer superconductors by quantitative high-resolution electron microscopy, *Zhang, Marks, Wang, Zhang, Dravid, Han and Payne* 57 (1995) 103
Measurement of lattice-fringe vectors from digital HREM images: experimental precision, *De Ruijter, Sharma, McCartney and Smith* 57 (1995) 409

Elsevier Science B.V.

Holography
Chromatic coherence and inelastic scattering in electron holography, *Cowley* 57 (1995) 327
Simulation of electron holographic contour maps of linear charged dislocations, *Cavalcoli, Matteucci and Muccini* 57 (1995) 385

Inelastic electron scattering theory
Chromatic coherence and inelastic scattering in electron holography, *Cowley* 57 (1995) 327

Microscopic methods, specifically for biological specimens
Proposal of alignment-independent classification of electron microscopic images with helical symmetry and its application to reconstituted thin filaments of skeletal muscle, *Ishikawa and Wakabayashi* 57 (1995) 91

Near field optical microscopy (NFOM)
Near-field fluorescent imaging of single proteins, *Dunn, Allen, Joyce, Anderson and Xie* 57 (1995) 113
Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 118
Photon scanning tunneling microscopy of optical channel waveguides, *Choo, Chudgar, Jackson, De Brabander, Kumar and Boyd* 57 (1995) 124
Applications of apertured photon scanning tunnelling microscopy (APSTM), *Tsai, Kovacs and Moskovits* 57 (1995) 130
Scanning near-field optic/atomic-force microscopy, *Muramatsu, Chiba, Ataka, Monobe and Fujihira* 57 (1995) 141
Comparison of different modes of reflection in near-field optical imaging, *Cline and Isaacson* 57 (1995) 147
Analysis of the near field image formation of dielectric gratings, *Chen and Kupka* 57 (1995) 153
Test of various diffraction theories in the near field of phase objects, *Totzeck and Krumbügel* 57 (1995) 160
Low temperature near field spectroscopy and microscopy, *Ghaemi, Cates and Goldberg* 57 (1995) 165
100 femtosecond/100 nanometer near-field probe, *Smith, Orr, Kopelman and Norris* 57 (1995) 173
Near-field optical microscopic recording on Langmuir–Blodgett (LB) films and chemically modified surfaces, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 176
Near-field, far-field and imaging properties of the 2D aperture SNOM, *Novotny, Pohl and Regli* 57 (1995) 180
Analysis of near field tip patterns including object interaction using finite-difference time-domain calculations, *Christensen* 57 (1995) 189
A perturbative diffraction theory of a multilayer system: applications to near-field optical microscopy SNOM and STOM, *Barchiesi and Van Labeke* 57 (1995) 196
Tip optics for illumination NSOM: extended-zone approach, *Yakobson and Paesler* 57 (1995) 204
Photodetector with subwavelength spatial resolution, *Kolb, Obermüller, Karraï, Abstreiter, Böhm, Tränkle and Weimann* 57 (1995) 208
Biological near-field scanning optical microscopy: instrumentation and sample issues for shear-force feedback, *Valaskovic, Holton and Morrison* 57 (1995) 212
Near-field optical microscopy at the liquid/air interface, *Seaver, Duncan and Frost* 57 (1995) 219
A simple technique for screening near-field probes, *Cloninger, Balasubramaniam, Boudreau, Raja and Hocken* 57 (1995) 223
Combined aperture SNOM/PSTM: best of both worlds?, *Hecht, Heinzelmann and Pohl* 57 (1995) 228
Scanning tunnelling optical microscopy – breaking a resolution barrier?, *Williamson, Binks and Miles* 57 (1995) 235
Kinetics, morphology and pulling regimes for sensing tips in near-field microscopy, *Yakobson and Paesler* 57 (1995) 241
Study of the features of PSTM images by means of a perturbative approach, *Sentenac and Greffet* 57 (1995) 246
Numerical analysis of a two-dimensional near-field probe, *Kann, Milster, Froehlich, Ziolkowski and Judkins* 57 (1995) 251
Implementation of an NSOM system for fluorescence microscopy, *Monson, Merritt, Smith, Langmore and Kopelman* 57 (1995) 257
Near field plasmon and force microscopy, *De Hollander, Van Hulst and Kooyman* 57 (1995) 263
Surface polaritons propagation along micropipettes, *Gurevich and Libenson* 57 (1995) 277
Locally resolved infrared spectroscopy, *Piednoir, Creuzet, Licoppe and Ortéga* 57 (1995) 282
Imaging of surface plasmon launch and propagation using a photon scanning tunneling microscope, *Dawson, Smith, De Fornel and Goudonnet* 57 (1995) 287
Contrast mechanisms and imaging modes in near field optical microscopy, *Toledo-Crow, Rogers, Seiferth and Vaez-Iravani* 57 (1995) 293
Optical contrast in near-field techniques, *Moers, Van Hulst, Ruiter and Bölger* 57 (1995) 298
Time as a contrast mechanism in near-field imaging, *LaRosa, Jahncke and Hallen* 57 (1995) 303
Optically trapped non-linear particles as probes for scanning near-field optical microscopy, *Hertz, Malmqvist, Rosengren and Ljungberg* 57 (1995) 309

Scanning probe optical microscopy using a metallic probe tip, *Kawata and Inouye* 57 (1995) 313
Near field optical microscopy using a metallic vibrating tip, *Gleyzes, Boccara and Bachelot* 57 (1995) 318

Reflection electron microscopy (REM) and reflection high energy electron diffraction (RHEED)
REM in a UHV TEM for the observation of dynamic phase transformation processes on the $Cu_3Au(111)$ surface, *Huang, Gajdardziska-Josifovska and Cowley* 57 (1995) 391

Specimen preparation and handling
A method for 2D crystallization of soluble proteins at liquid–liquid interface, *Aoyama, Ogawa, Kimura and Fujiyoshi* 57 (1995) 345

Spectroscopy in NFOM
Measurements of lateral distribution of fluorescence intensities and fluorescence spectra of microareas by a combined SNOM and AFM, *Fujihira, Monobe, Muramatsu and Ataka* 57 (1995) 118
Low temperature near field spectroscopy and microscopy, *Ghaemi, Cates and Goldberg* 57 (1995) 165
Locally resolved infrared spectroscopy, *Piednoir, Creuzet, Licoppe and Ortéga* 57 (1995) 282

Tip scanning instrument design and characterization
Scanning near-field optic/atomic-force microscopy, *Muramatsu, Chiba, Ataka, Monobe and Fujihira* 57 (1995) 141
Comparison of different modes of reflection in near-field optical imaging, *Cline and Isaacson* 57 (1995) 147
Low temperature near field spectroscopy and microscopy, *Ghaemi, Cates and Goldberg* 57 (1995) 165
Characterization of the temporal behavior of ultrashort pulses emerging from a near-field fiber probe, *Dunn and Xie* 57 (1995) 169
100 femtosecond/100 nanometer near-field probe, *Smith, Orr, Kopelman and Norris* 57 (1995) 173
Photodetector with subwavelength spatial resolution, *Kolb, Obermüller, Karraï, Abstreiter, Böhm, Tränkle and Weimann* 57 (1995) 208
Biological near-field scanning optical microscopy: instrumentation and sample issues for shear-force feedback, *Valaskovic, Holton and Morrison* 57 (1995) 212
A simple technique for screening near-field probes, *Cloninger, Balasubramaniam, Boudreau, Raja and Hocken* 57 (1995) 223
Combined aperture SNOM/PSTM: best of both worlds?, *Hecht, Heinzelmann and Pohl* 57 (1995) 228
Kinetics, morphology and pulling regimes for sensing tips in near-field microscopy, *Yakobson and Paesler* 57 (1995) 241
Implementation of an NSOM system for fluorescence microscopy, *Monson, Merritt, Smith, Langmore and Kopelman* 57 (1995) 257
Near-field magneto-optics with polarization sensitive STOM, *Safarov, Kosobukin, Hermann, Lampel, Marlière and Peretti* 57 (1995) 270
Scanning probe optical microscopy using a metallic probe tip, *Kawata and Inouye* 57 (1995) 313
Near field optical microscopy using a metallic vibrating tip, *Gleyzes, Boccara and Bachelot* 57 (1995) 318

Theoretical aspects of NFOM
Analysis of the near field image formation of dielectric gratings, *Chen and Kupka* 57 (1995) 153
Test of various diffraction theories in the near field of phase objects, *Totzeck and Krumbügel* 57 (1995) 160
Near-field, far-field and imaging properties of the 2D aperture SNOM, *Novotny, Pohl and Regli* 57 (1995) 180
Analysis of near field tip patterns including object interaction using finite-difference time-domain calculations, *Christensen* 57 (1995) 189
A perturbative diffraction theory of a multilayer system: applications to near-field optical microscopy SNOM and STOM, *Barchiesi and Van Labeke* 57 (1995) 196
Tip optics for illumination NSOM: extended-zone approach, *Yakobson and Paesler* 57 (1995) 204
Numerical analysis of a two-dimensional near-field probe, *Kann, Milster, Froehlich, Ziolkowski and Judkins* 57 (1995) 251